

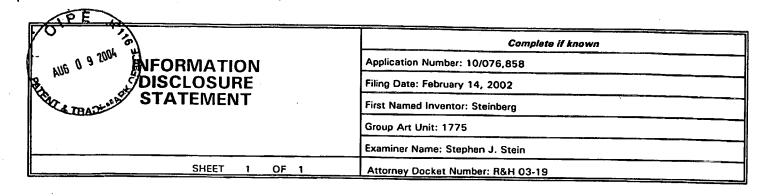
UNITED STATES PATENT DOCUMENTS						
EXAMINER'S INITIALS	CITE NO.	PATENT NUMBER	ISSUE DATE MM-DD-YYYY	FIRST NAMED INVENTOR		
535		6595700	07/22/2003	Steinberg, et al.		
SJS		6738145	05/18/2004	Sherrer, et al.		
১ ব১		2001/0055460	12/27/2001	Steinberg		
	<u> </u>					

FOREIGN PATENT DOCUMENTS						
EXAMINER'S CITE DOCUMENT COUNTRY OR DATE OF FIRST NAMED INVENTOR INITIALS NO. NUMBER REGION PUBLICATION APPLICANT						
212		WO 03/027734	wo	04/03/2003	Jeantil, et al.	

OTHER PRIOR ART - NON-PATENT DOCUMENTS						
EXAMINER'S INITIALS	CITE NO.	Include name of the author (in Capital Letters), title of the article (when appropriate), title of the item(book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published				

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UNITED STATES PATENT DOCUMENTS							
EXAMINER'S INITIALS	CITE NO.	PATENT NUMBER	ISSUE DATE MM-DD-YYYY	FIRST NAMED INVENTOR			
<i>5</i> 35		4810557	03/07/1989	Blonder			
232		4837129	06/06/1989	Frisch et al.			
535		4863560	09/05/1989	Hawkins			
222		4904036	02/27/1990	Blonder			
222		4938841	07/03/1990	Shahar et al.			
322		4957592	09/18/1990	O'Neill			
575		5338400	08/16/1994	Jerman			
222		5478438	12/26/1995	Nakanishi et al.			
252.		5479426	12/26/1995	Nakanishi et al.			
275		5611006	03/11/1997	Tabuchi			
535		5911021	06/08/1999	MacDonald et al.			
575		6132107	10/17/2000	Morikawa			
· 222		6187515	02/13/2001	Tran et al.			
732		6257772	07/10/2001	Nakanishi et al.			
• 222		6553173	04/22/2003	Gotó			
578		6567590	05/20/2003	Okada et al.			
222		US 2002/0195417	12/26/2002	Steinberg			
222		US 2003/0020130	01/30/2003	Steinberg et al.			
222		US 2003/0067069	04/10/2003	Steinberg et al.			
<i>১</i> হ্ব		US 2003/0021572	01/30/2003	Steinberg			

FOREIGN PATENT DOCUMENTS								
EXAMINER'S CITE DOCUMENT COUNTRY OR DATE OF PUBLICATION FIRST NAMED INVENTOR OF MM-DD-YYYY APPLICANT								

OTHER PRIOR ART - NON-PATENT DOCUMENTS						
EXAMINER'S INITIALS	CITE NO.	Include name of the author (in Capital Letters), title of the article (when appropriate), title of the item(book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published				
>35		Nijdam, et al. "Etching of silicon in alkaline solutions: a crtical look at the {111} minimum," MESA				
335		Oosterbroek, et al. "New design methodologies in <111> oriented silicon wafers," MESA				
<u> ১ব১</u>		Suchtelen, et al. "Simulation of Anisotropic Wet-Chemical Etching Using a Physical Model," MESA				

EXAMINER'S SIGNATURE	Si	La	Ste.	DATE CONSIDERED	9/	4/2004
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